



IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-02

CB Certificate No.: 20002490 ITL

Schedule Number: IECQ-L ULTW 16.0003-02-S Rev No.: 7 Revision Date: 2024/08/29 Page 1 of 1

Appendix-1 (20002490 ITL)

Schedule of Scope to Certificate of Approval

Description test	Standard
Scanning Electron Microscope (SEM)	T-SEM-3
Energy Dispersive Spectrometry of X-ray (EDS)	T-SEM-3, T-TEM-3
Focused Ion Beam microscope (FIB)	T-FIB-3
X-Ray imaging	T-EFA-3
Scanning Acoustic Tomography (SAT)	T-EFA-3
Optical Microscope (OM)	T-OMI-3
3D Optical Microscope (3D OM)	T-LAB-3
IC Layout Imaging	T-OMI-3
Circuitry analysis	T-OMI-3

Technical Reviewer of DQS: Paul Yang Date: 8/29/2024

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org

DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan

